

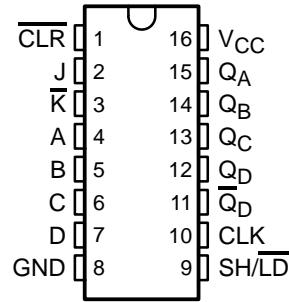
SN74AS195

4-BIT BIDIRECTIONAL UNIVERSAL SHIFT REGISTER

SDAS138B – DECEMBER 1983 – REVISED JANUARY 1995

- Parallel-to-Serial, Serial-to-Parallel Conversions
- Parallel Synchronous Loading
- J and \bar{K} Inputs to First Stage
- Right Shift Only With Complementary Outputs on Last Stage
- Direct Overriding Clear
- Package Options Include Plastic Small-Outline (D) Packages and Standard Plastic (N) 300-mil DIPs

D OR N PACKAGE
(TOP VIEW)



description

This 4-bit bidirectional universal shift register features parallel (A, B, C, D) inputs, parallel (Q_A , Q_B , Q_C , Q_D , \bar{Q}_D) outputs, J- \bar{K} serial (J, \bar{K}) inputs, shift/load control (SH/\bar{LD}) input, and a direct overriding clear (\bar{CLR}). The registers have two modes of operation:

- Parallel (broadside) load
- Shift (in the direction Q_A toward Q_D)

Parallel loading is accomplished by applying the four bits of data and taking SH/\bar{LD} low. The data is loaded into the associated flip-flops and appears at the outputs after the positive transition of the clock (CLK) input. During loading, serial data flow is inhibited.

Shifting is accomplished synchronously when SH/\bar{LD} is high. Serial data for this mode is entered at the J- \bar{K} inputs. These inputs permit the first stage to perform as a J- \bar{K} , D-, or T-type flip-flop as shown in the function table.

The SN74AS195 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

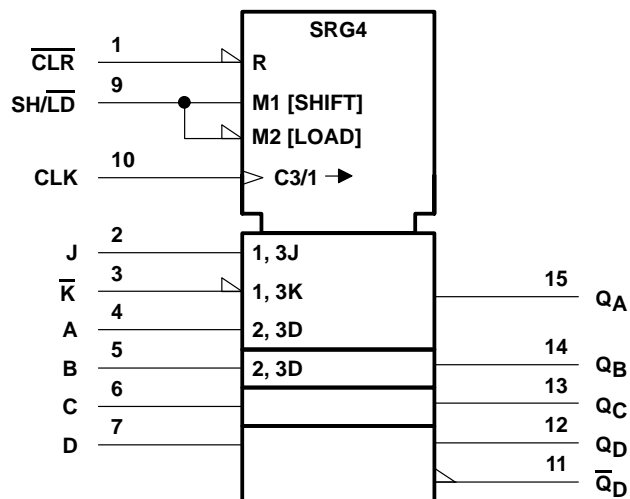
INPUTS								OUTPUTS					
$\overline{\text{CLR}}$	$\text{SH}/\overline{\text{LD}}$	CLK	SERIAL		PARALLEL				Q_A	Q_B	Q_C	Q_D	\overline{Q}_D
			J	\overline{K}	A	B	C	D					
L	X	X	X	X	X	X	X	X	L	L	L	L	H
H	L	\uparrow	X	X	a	b	c	d	a	b	c	d	\overline{d}
H	H	L	X	X	X	X	X	X	Q_{A0}	Q_{B0}	Q_{C0}	Q_{D0}	$\overline{Q_{D0}}$
H	H	\uparrow	L	H	X	X	X	X	Q_{A0}	Q_{A0}	Q_{Bn}	Q_{Cn}	$\overline{Q_{Cn}}$
H	H	\uparrow	L	L	X	X	X	X	L	Q_{An}	Q_{Bn}	Q_{Cn}	$\overline{Q_{Cn}}$
H	H	\uparrow	H	H	X	X	X	X	H	Q_{An}	Q_{Bn}	Q_{Cn}	$\overline{Q_{Cn}}$
H	H	\uparrow	H	L	X	X	X	X	$\overline{Q_{An}}$	Q_{An}	Q_{Bn}	Q_{Cn}	$\overline{Q_{Cn}}$

SN74AS195

4-BIT BIDIRECTIONAL UNIVERSAL SHIFT REGISTER

SDAS138B – DECEMBER 1983 – REVISED JANUARY 1995

logic symbol†

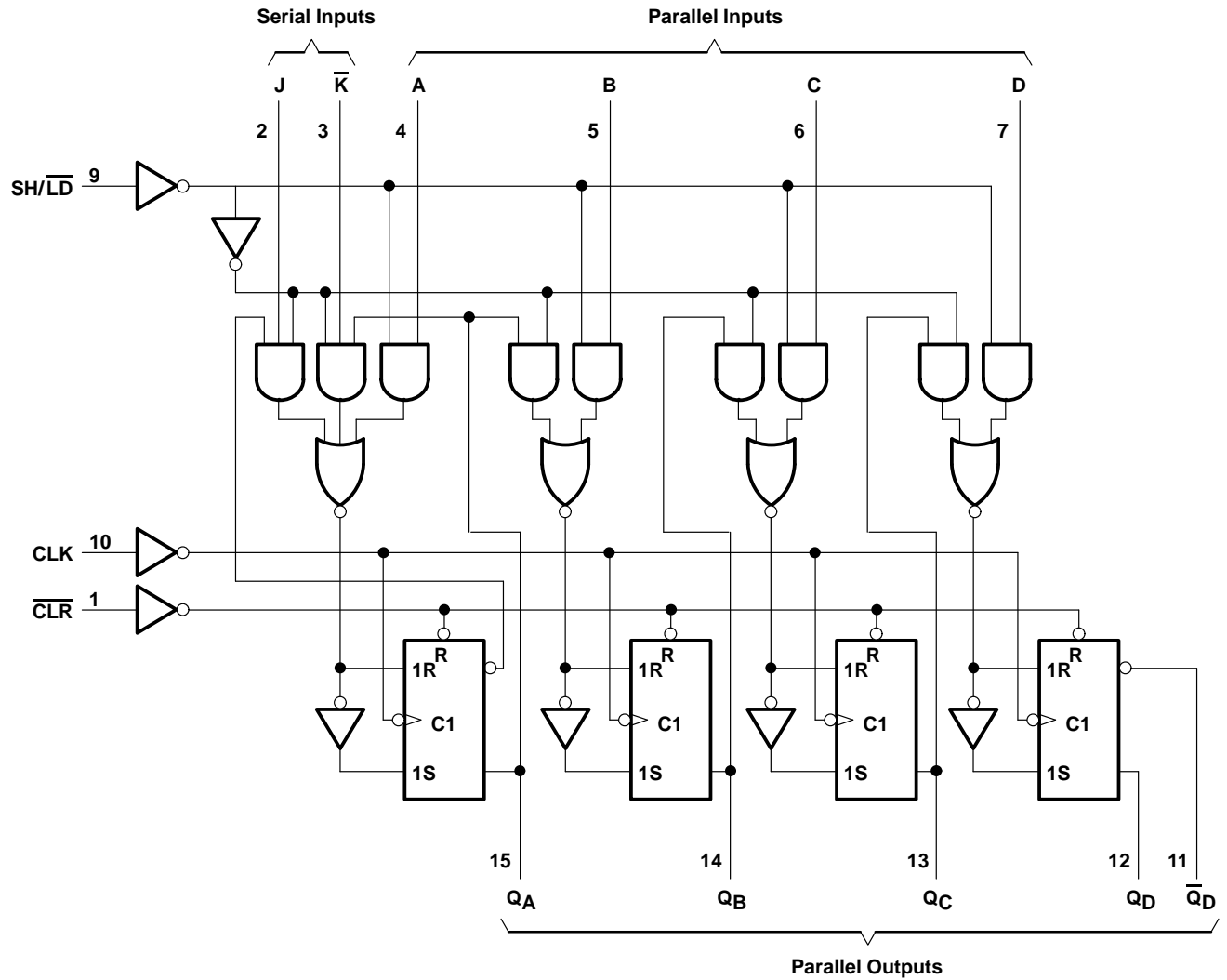


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN74AS195
4-BIT BIDIRECTIONAL UNIVERSAL SHIFT REGISTER

SDAS138B – DECEMBER 1983 – REVISED JANUARY 1995

logic diagram (positive logic)



SN74AS195

4-BIT BIDIRECTIONAL UNIVERSAL SHIFT REGISTER

SDAS138B – DECEMBER 1983 – REVISED JANUARY 1995

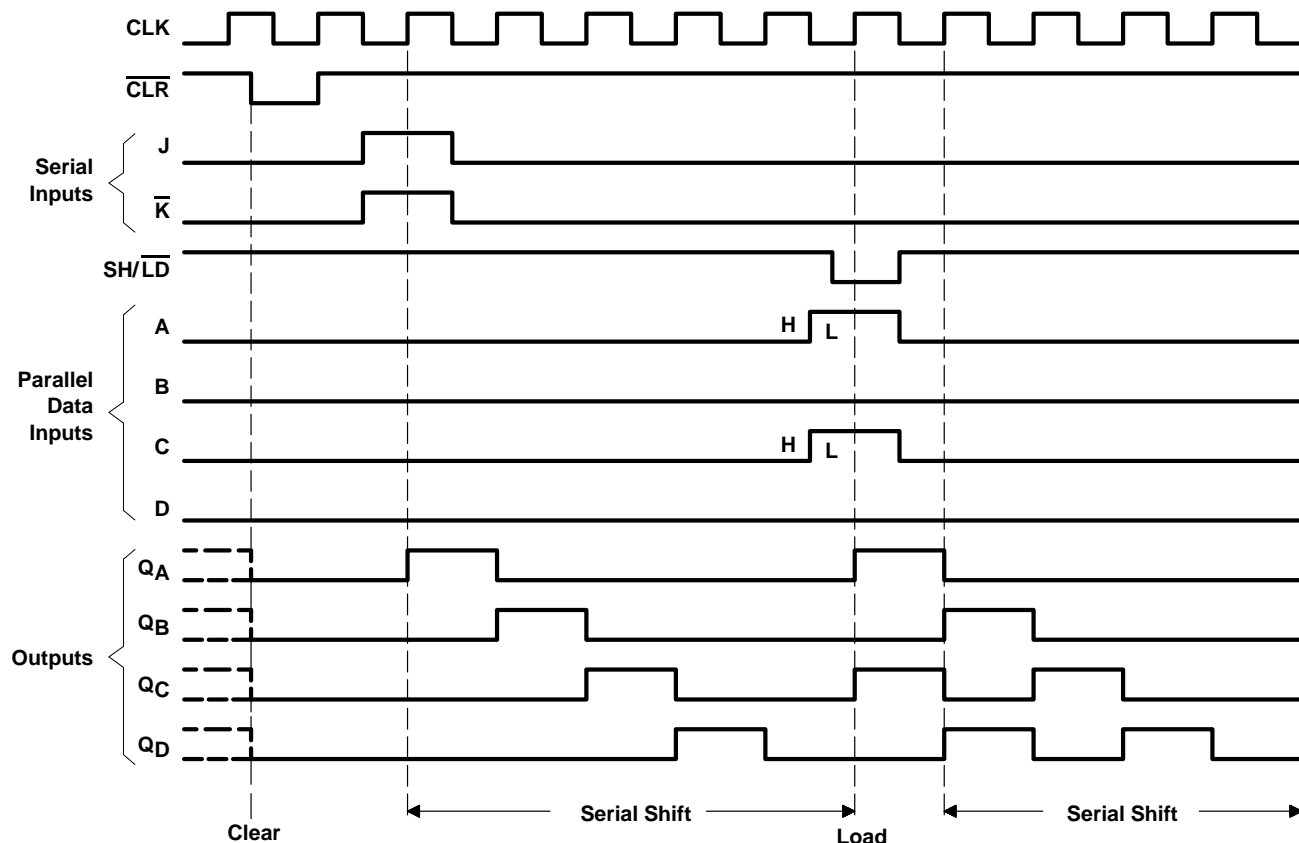


Figure 1. Typical Clear, Shift, and Load Sequences

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V_{CC}	7 V
Input voltage, V_I	7 V
Operating free-air temperature range, T_A	0°C to 70°C
Storage temperature range	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

SN74AS195

4-BIT BIDIRECTIONAL UNIVERSAL SHIFT REGISTER

SDAS138B – DECEMBER 1983 – REVISED JANUARY 1995

recommended operating conditions

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
I_{OH}	High-level output current			-2	mA
I_{OL}	Low-level output current			20	mA
f_{clock}	Clock frequency	0		70	MHz
t_w	Pulse duration	CLK high	4		ns
		CLR low	7.2		
t_{su}	Setup time	Data before CLK↑	3.5		ns
		SH/LD before CLK↑	8		
		CLR high before CLK↑	6		
t_h	Hold time	Data after CLK↑	1		ns
		SH/LD after CLK↑	0		
T_A	Operating free-air temperature	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V_{IK}		$V_{CC} = 4.5\text{ V}$,	$I_I = -18\text{ mA}$			-1.2	V
V_{OH}		$V_{CC} = 4.5\text{ V to } 5.5\text{ V}$,	$I_{OH} = -2\text{ mA}$	$V_{CC}-2$			V
V_{OL}		$V_{CC} = 4.5\text{ V}$,	$I_{OL} = 20\text{ mA}$		0.35	0.5	V
I_I	SH/LD	$V_{CC} = 5.5\text{ V}$,	$V_I = 7\text{ V}$			0.2	mA
	All others					0.1	
I_{IH}	SH/LD	$V_{CC} = 5.5\text{ V}$,	$V_I = 2.7\text{ V}$			40	μA
	All others					20	
I_{IL}	SH/LD	$V_{CC} = 5.5\text{ V}$,	$V_I = 0.4\text{ V}$			-1	mA
	All others					-0.5	
$I_O‡$		$V_{CC} = 5.5\text{ V}$,	$V_O = 2.25\text{ V}$	-30		-112	mA
I_{CCH}		$V_{CC} = 5.5\text{ V}$			32	51	mA
I_{CCL}		$V_{CC} = 5.5\text{ V}$			36	57	mA

† All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$.

‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS} .



SN74AS195

4-BIT BIDIRECTIONAL UNIVERSAL SHIFT REGISTER

SDAS138B – DECEMBER 1983 – REVISED JANUARY 1995

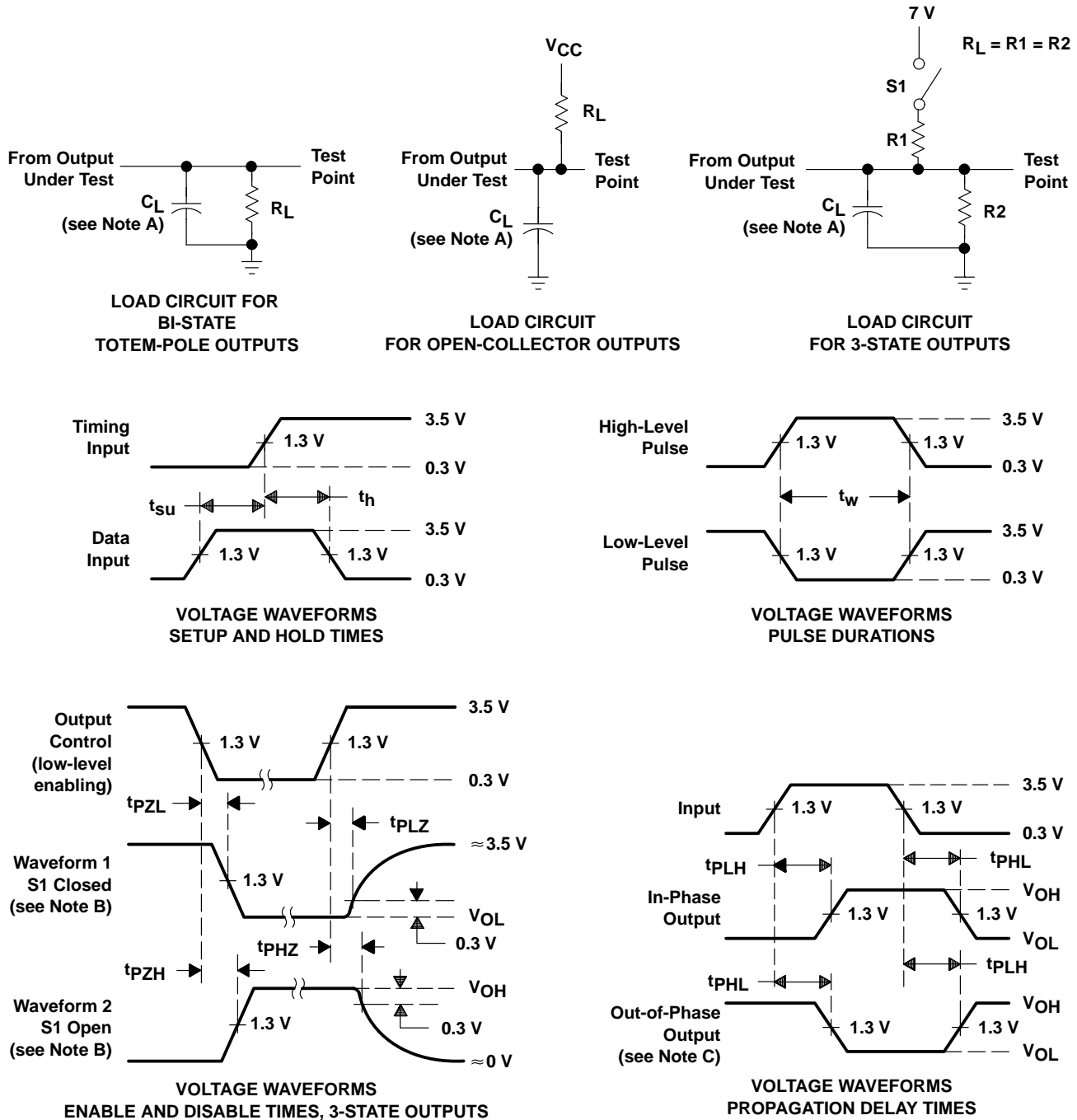
switching characteristics (see Figure 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R _L = 500 Ω, T _A = MIN to MAX†		UNIT
			MIN	MAX	
f _{max}			70		MHz
t _{PLH}	CLK	Any Q	3	8.5	ns
t _{PHL}			2.5	10.5	
t _{PLH}	$\overline{\text{CLR}}$	$\overline{\text{Q}}_{\text{D}}$	4	8	ns
t _{PHL}		Q _A thru Q _D	5	11.5	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



**PARAMETER MEASUREMENT INFORMATION
 SERIES 54ALS/74ALS AND 54AS/74AS DEVICES**



- NOTES: A. C_L includes probe and jig capacitance.
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
 D. All input pulses have the following characteristics: $PRR \leq 1$ MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
 E. The outputs are measured one at a time with one transition per measurement.

Figure 2. Load Circuits and Voltage Waveforms

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.